

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-1724SERIAL NO.  
09/905,286LIST OF ART CITED BY APPLICANT  
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Cem Basceri et al.FILING DATE  
July 13, 2001GROUP  
1762

## U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
EF	AA 4,261,698	04/81	Carr et al.			
	AB 4,691,662	09/87	Roppel et al.			
	AC 5,261,961	11/93	Takasu et al.			
	AD 5,270,241	12/93	Dennison et al.			
	AE 5,312,783	05/94	Takasaki et al.			
	AF 5,392,189	02/95	Fazan et al.			
	AG 5,395,771	03/95	Nakato			
	AI 5,468,687	11/95	Carl et al.			
	AJ 5,525,156	06/96	Manada et al.			
	AJ 5,614,018	03/97	Azuma et al.			
	AK 5,656,329	08/97	Hampden-Smith			
EF	AL 5,663,089	09/97	Tomozawa et al.			

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	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
EF	AM EP 0 030 798	06/81	EPO				
1	AN GB 2 194 555 A	03/88	United Kingdom				
	AO EP 0 306 069 A2	03/89	EPO				
	AP EP 0 388 957 A2	09/90	EPO				
EF	AQ JP2250970	10/90	Japan				

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

EF	AR	Aoyama et al., <i>Leakage Current Mechanism of Amorphous and Polycrystalline Ta<sub>2</sub>O<sub>5</sub> Films Grown by Chemical Vapor Deposition</i> , 143 J. ELECTROCHEM SOC., No. 3, pp 977-983 (March 1996).
		Stemmer et al., <i>Accommodation of nonstoichiometry in (100) fiber-textured (Ba<sub>x</sub>Sr<sub>1-x</sub>)Ti<sub>1+y</sub>O<sub>3+z</sub> thin films grown by chemical vapor deposition</i> , 74 APPL. PHYS. LETT., No. 17, pp. 2432-2434 (26 April 1999).
EF	AT	Streiffer et al., <i>Ferroelectricity in thin films: The dielectric response of fiber-textured (Ba<sub>x</sub>Sr<sub>1-x</sub>)Ti<sub>1+y</sub>O<sub>3+z</sub> thin films grown by chemical vapor deposition</i> , 86 J. APPL. PHYS. No. 8, pp. 4565-4575 (15 October 1999).

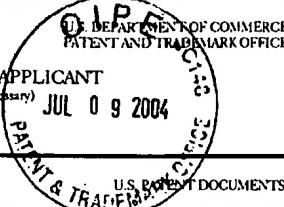
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
EF	AA	5,702,562	12/97	Wakahara			
	AB	5,719,417	02/98	Roeder et al.			
	AC	5,723,361	03/98	Azuma et al.			
	AD	5,736,759	04/98	Haushalter			
	AE	5,976,990	11/99	Mercaldi et al.			
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	AG	6,101,085	08/00	Kawahara et al.			
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	AI	6,258,654	07/01	Goch			
	AJ	6,287,935 B1	09/01	Coursey			
	AK	6,325,017 B1	12/01	DeBoer et al.			
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							Yes	No
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	AN	04-115533	04/92	Japan				
	AO	04-180566	06/92	Japan				
	AP	08-060347	03/96	Japan				
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
EF	AM	6,566,147 B2	05/03	Basceri et al.			
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							Yes	No
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	AP							
	AQ							

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Examiner NAME & TRADEMARK OFFICE	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
EF	AA 6,337,496 B2	01-2002	Jung			
EF	AB 6,507,060 B2	01-2003	Ren et al.			
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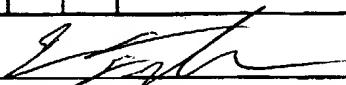
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